

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS1302	Sep-97	9733 A3	ANAM, K.	DN720044AAA	0.8μ OX/NI (2 MTL)	08 SOIC 150

STRESS/JOB NO.

**READPOINT
(Sample Size/No. of Fails)**

Preconditioning (P/C): HTC Vapor Phase P-20425	<u>Electrical</u>	<u>Cum %</u>
	235/0	0.0%

Infant / High Voltage Life 125°C, 6.0 V. P-20464, P-20566	<u>48 Hr</u>	<u>336 Hr</u>	<u>1KHr</u>	<u>*Failure Rate</u>
	231/0	77/0	77/0	82 Fits

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle -55°C to +125°C P-20567	<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
	39/0	39/0	0.0%

Biased Moisture 85°C/85% RH, 5.5 V. P-20568	<u>274 Hr</u>	<u>959 Hr</u>	<u>Cum %</u>
	77/0	77/0	0.0%

Autoclave 121°C/100% RH, 2 Atoms P-20569	<u>96 Hr</u>	<u>Cum %</u>
	38/0	0.0%

Failure Mode

Failure Analysis